

MOS FIELD EFFECT TRANSISTOR **2SK4145**

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The 2SK4145 is N-channel MOS Field Effect Transistor designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE
2SK4145-S19-AY	Pure Sn (Tin)	Tube	TO-220
		50p/tube	typ. 1.9 g

FEATURES

Low on-state resistance

 $R_{DS(on)}$ = 10 $m\Omega$ MAX. (Vgs =10 V, Ip =42A)

• Low Ciss: Ciss = 5300 pF

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

VDSS	60	V
Vgss	±20	V
I _{D(DC)}	±84	Α
D(pulse)	±215	Α
P _{T1}	84	W
P _{T2}	1.5	W
T_ch	150	°C
T_{stg}	-55 to +150	°C
las	32	Α
Eas	102	mJ
	VGSS ID(DC) ID(pulse) PT1 PT2 Tch Tstg IAS	VGSS ±20 ID(DC) ±84 ID(pulse) ±215 PT1 84 PT2 1.5 Tch 150 Tstg -55 to +150 IAS 32

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = 30 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V, L=100uH

THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	1.49	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

Note

2SK4145 is sorted BVDSS = 68V at ID = 250uA, VGS = 0 after assembly.

The information contained in this document is being issued in advance of the production cycle for the device. The parameters for the device may change before final production or NEC Corporation, at its own discretion, may withdraw the device prior to its production. Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

Data update: January 29th, 2007

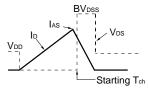


ELECTRICAL CHARACTERISTICS (TA = 25°C)

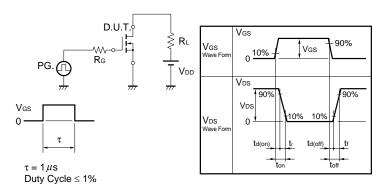
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V _{DS} = 60V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10V , I _D =1 mA	2.0		4.0	V
Forward Transfer Admittance	y fs	V _{DS} = 10 V, I _D = 30A	16.4			S
Drain to Source On-state Resistance	R _{DS(on)}	Vgs = 10 V, ID = 42A		7	10	$m\Omega$
Input Capacitance	Ciss	V _{DS} = 10 V		5300		pF
Output Capacitance	Coss	Vgs = 0 V		540		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		330		pF
Turn-on Delay Time	t _{d(on)}	VDD = 30 V, ID = 42A		25		ns
Rise Time	tr	Vgs = 10 V		17		ns
Turn-off Delay Time	t _{d(off)}	$R_G = 0 \Omega$		66		ns
Fall Time	tf			9		ns
Total Gate Charge	Q _G	VDD = 48 V		90		nC
Gate to Source Charge	Qgs	V _{GS} = 10 V		21		nC
Gate to Drain Charge	Q _{GD}	ID = 84A		30		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 84A, VGS = 0 V		1.0	1.5	V
Reverse Recovery Time	trr	IF = 84A, VGS = 0 V		43		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		62		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY

$V_{GS} = 20 \rightarrow 0 \text{ V}$ $PG. \bigcirc PG. \bigcirc PG.$



TEST CIRCUIT 2 SWITCHING TIME



TEST CIRCUIT 3 GATE CHARGE

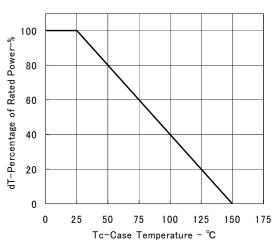
$$\begin{array}{c|c} D.U.T. \\ \hline I_G = 2 \text{ mA} \\ \hline \end{array}$$

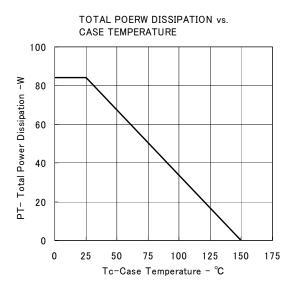
$$\begin{array}{c|c} PG. & \\ \hline \end{array} \begin{array}{c} S & \Omega \\ \hline \end{array} \begin{array}{c} D.U.T. \\ \hline \end{array}$$

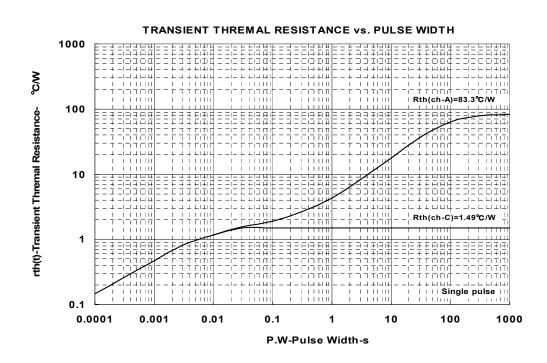


TYPICAL CHARACTERISTICS $(T_A = 25^{\circ}C)$



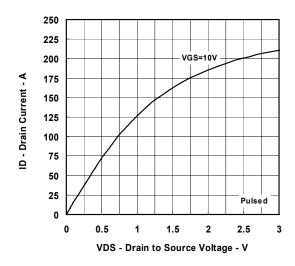


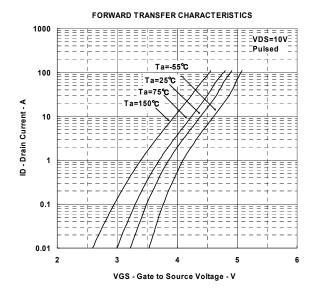




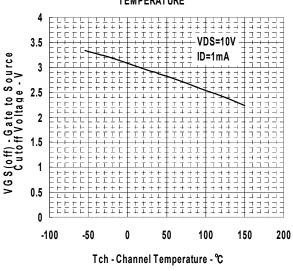


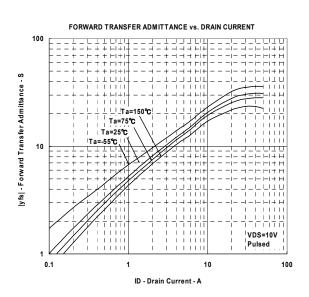
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



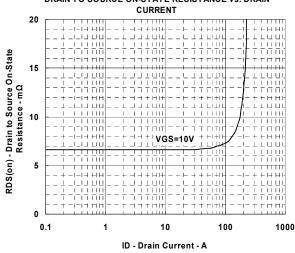


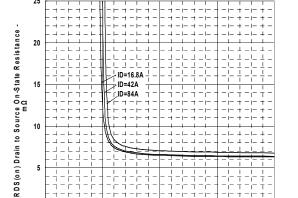
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE





DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN

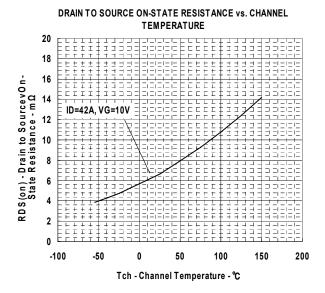




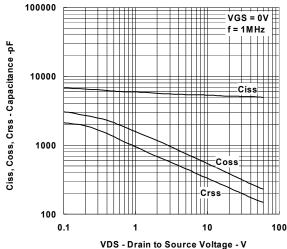
VGS - Gate to Source Voltage - V

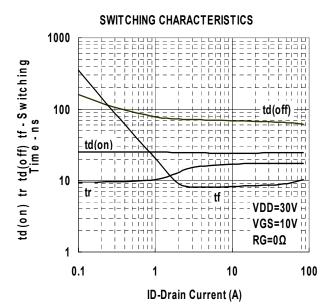
0

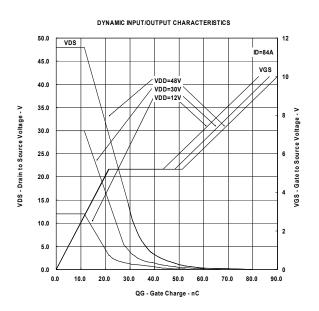
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

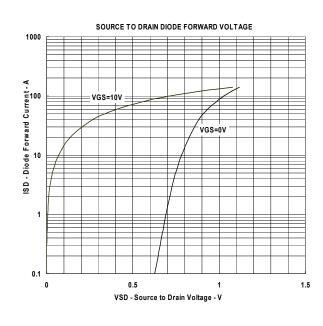


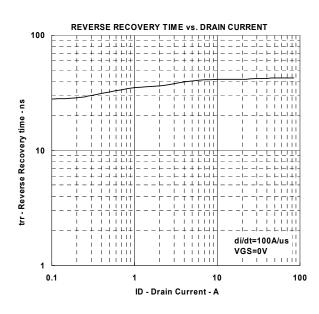
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE







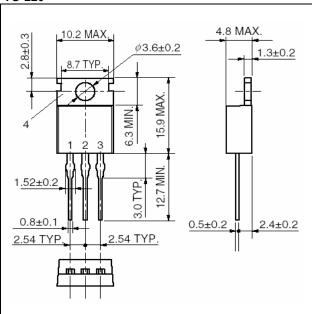




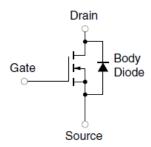


PACKAGE DRAWING (Unit: mm)

TO-220



EQUIVALENT CIRCUIT



Remark

Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.



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